

U.S. Department of Commerce, Patent and Trademark Office

Application No.: 10/748,829

Filing Date: December 29, 2003

First Named Inventor: Weidong Yang

Group Art Unit: Unknown

Examiner Name: Unknown

Confirmation No.: Unknown

Attorney Docket No.: NAN066 US

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)



U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
DR	1.	5,214,492	25-May-93	LoBianco et al.	356	400	8/2/1991
	2.	5,216,257	Jun. 1, 1993	Brueck et al.	250	548	7/9/1990
	3.	5,307,152	Apr. 26, 1994	Boehnlein et al.	356	376	9/29/1992
	4.	5,559,601	Sep. 24, 1996	Gallatin et al.	356	363	1/24/1994
	5.	5,805,290	Sep. 8, 1998	Ausschnitt et al.	356	401	5/2/1996
	6.	5,969,819	Oct. 19, 1999	Wang	356	371	6/5/1997
	7.	6,077,756	Jun. 20, 2000	Lin et al.	438	401	4/24/1998
	8.	6,084,712	Jul. 4, 2000	Harding	359	618	11/3/1998
	9.	6,130,750	Oct. 10, 2000	Ausschnitt et al.	356	401	8/28/1997
	10.	6,407,396	Jun. 18, 2002	Mih et al.	250	491.1	6/24/1999
	11.	6,429,930	Aug. 6, 2002	Littae et al.	356	124	9/6/2000
	12.	US 2002/0135875	Sep. 26, 2002	Niu et al.	359	564	2/27/2001
	13.	US 2002/0158193	Oct. 31, 2002	Sezginer et al.	250	237	2/12/2001
	14.	US 2003/0002043	Jan. 2, 2003	Abdulhalim et al.	356	400	4/10/2001
	15.	US 2003/0042579	Mar. 6, 2003	Schulz	257	629	8/30/2001
	16.	US 2003/0043372	Mar. 6, 2003	Schulz	356	327	8/30/2001
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	18.	US 2003/0044702	Mar. 6, 2003	Schulz	430	30	8/30/2001
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Foreign Patent Documents

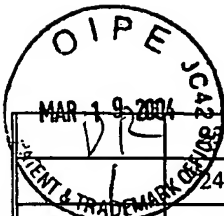
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
DR	20.	WO 01/84382 A1	Nov. 8, 2001	PCT	G06F	17/50	5/4/2000	
	21.	WO 02/065545 A2	Aug. 22, 2002	PCT	H01L	21/66	2/12/2001	
✓	22.	WO 02/069390 A2	Sep. 6, 2002	PCT	H01L	21/66	2/27/2001	

Examiner

Date Considered

7/16/07

*EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.



23.	WO 02/084213 A1	Oct. 24, 2002	PCT	G01B	Nov-00	4/10/2001	
24.	WO 02/25723 A2	Mar. 28, 2002	PCT	H01L	21/66	9/19/2000	
25.	WO 04/008068 A1	Jan. 22, 2004	PCT	G01B	11/27	10/26/01	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

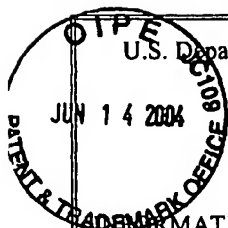
26.	Bischoff, J. et al., "Light Diffraction Based Overlay Measurement" <i>Proceedings of SPIE</i> , Vol. 4344 (2001) Pages 222-233
27.	Michaelis, A. et al., "Spectroscopic Anisotropy Micro-Ellipsometry (SAME) for determination of lateral and vertical dimensions of sub-micron lithographic structures" IEEE Catalog Number 99TH8453 (1999) Pages 131-134
28.	NanoWave:Technology/development tools, http://www.nanowave.com/technology_applications/tech_devtoolsPR.html , 2 pages, downloaded April 9, 2002.
29.	NanoWave:Technology/how it works, http://www.nanowave.com/technology_applications/tech_HIWPR.html , 3 pages, downloaded April 9, 2002.
30.	NanoWave:Technology/product design, http://www.nanowave.com/technology_applications/tech_designPR.html , 4 pages, downloaded April 9, 2002.
31.	D.C. Flanders & Henry I. Smith, "A new interferometric alignment technique", Applied Physics Letters, Vol. 31, No. 7, 1 October 1977, pp. 426-428

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Application No.: 10/748,829

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First Named Inventor: Weidong Yang

Group Art Unit: 2621

Examiner Name: Unknown

Confirmation No.: 7169

Attorney Docket No.: NAN066 US

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(Use several sheets if necessary)

U.S. Patent Documents

*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
DR	32	US 2004/0101983	05/27/04	Jones et al.	438	14	
b	33	US 6,458,605	10/01/02	Stirton	438	7	

Foreign Patent Documents

							Translation	
		Document	Date	Country	Class	Subclass	Yes	No

Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner: *[Signature]*

Date Considered: 7/16/07

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DR
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[Signature]
7/16/07

	Serial No.:	First Named Inventor	Date:
1.	10/116,863	Weidong Yang	Apr. 4, 2002
2.	10/116,964	Weidong Yang	Apr. 4, 2002
3.	10/116,798	Weidong Yang	Apr. 4, 2002
4.	10/116,855	John D. Heaton	Apr. 4, 2002
5.	10/261,547	Weidong Yang	Sep. 30, 2002
6.	10/422,232	Blaine R. Spady	Apr. 23, 2003
7.	09/960,892	Roger R. Lowe-Webb	Sep. 20, 2001

The Applicants presume that the Examiner has access to and will review the co-pending applications and the files thereof for any office actions, amendments or other materials that may be relevant to the patentability of the claims of the present application. For any such U.S. patent application(s) that are currently pending, the Applicants further presume that the Examiner will consider any future office actions, amendments or other materials in the file thereof that may be relevant to the patentability of the claims herein. **If the Applicants' understanding in this regard is not correct, please notify the undersigned so that copies of any such documents can be submitted to the Examiner with the necessary precautions so that the file may be expunged of any proprietary information that is considered unimportant to a reasonable examiner.**

All of the co-pending applications in the above list are unpublished. Applicants do not believe that it is proper for any of the listed applications to appear on the face of a patent that may issue from the present application, and accordingly, Applicants have not listed these applications on a PTO-Form 1449.

The information contained in this Information Disclosure Statement under 37 C.F.R. §1.555 is to the best of my knowledge and is not to be construed as a representation that: (i) a complete search has been made; (ii) additional information material to the examination of this application does not exist; (iii) the information, protocols, results and the like reported by third parties are accurate or enabling; or (iv) the above information constitutes prior art to the subject invention.

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